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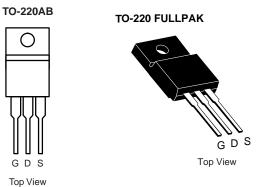
# N-Channel 800V (D-S) Power MOSFET

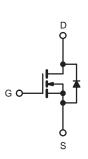
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	800					
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	1.3				
Q <sub>g</sub> (Max.) (nC)	33					
Q <sub>gs</sub> (nC)	6					
Q <sub>gd</sub> (nC)	17					
Configuration	Single					

### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS (T</b> <sub>C</sub>	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	800	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	7		
		T <sub>C</sub> = 100 °C		4.4	A	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28	1	
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	650	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.8	A	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		PD	190	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
				1.1	N · m	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 23 mH,  $R_g = 25 \Omega$ ,  $I_{AS} = 7.8 \text{ A}$  (see fig. 12). c.  $I_{SD} \leq 7.8 \text{ A}$ , dl/dt  $\leq 140 \text{ A/}\mu\text{s}$ ,  $V_{DD} \leq 600 \text{ V}$ ,  $T_J \leq 150 \text{ °C}$ .

d. 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply



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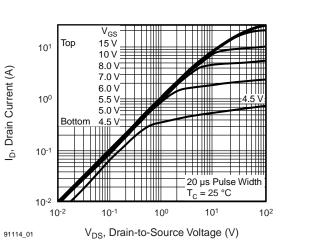
THERMAL RESISTANCE RATII	NGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 40 0.24 -			°C/W			
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>							
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 0.65				L		
<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static		1				•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 2	250 µA	800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20	V	-	-	± 100	nA
	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V	<sub>iS</sub> = 0 V	-	-	1			
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 640 V	/, V <sub>GS</sub> = 0 \	/, T <sub>J</sub> = 125 °C	-	-	45	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	١ <sub>D</sub>	a = 3.7 A <sup>b</sup>	-	1.3	1.8	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =	= 100 V, I <sub>D</sub> =	= 3.7 A <sup>b</sup>	4.5	-	-	S
Dynamic		1				<b></b>	1	
Input Capacitance	C <sub>iss</sub>				-	1120	-	
Output Capacitance	C <sub>oss</sub>			-	115	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	f = 1.0 MHz, see fig. 5		-	27	-	
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V}$ $I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$	-	-	33		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		A, V <sub>DS</sub> = 400 V, ig. 6 and 13 <sup>b</sup>	-	-	6	nC
Gate-Drain Charge	Q <sub>gd</sub>		366 1		-	-	17	
Turn-On Delay Time	t <sub>d(on)</sub>			-	18	-		
Rise Time	tr		$V_{DD} = 400 \text{ V}, \text{ I}_D = 3.8 \text{ A},$ $R_g = 6.2 \Omega, R_D = 52 \Omega$		-	30	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	R <sub>g</sub> =			-	76	-	
Fall Time	t <sub>f</sub>	see fig. 10 <sup>b</sup>			-	33	-	1
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH	
Internal Source Inductance	L <sub>S</sub>			-	13	-		
Drain-Source Body Diode Characteristic	S	<u></u>					1	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	A	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	21		
Body Diode Voltage	V <sub>SD</sub>	$T_{\rm J}$ = 25 °C, $I_{\rm S}$ = 3.8 A, $V_{\rm GS}$ = 0 V <sup>b</sup>		-	-	1.8	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_{\rm J} = 25 ^{\circ}{\rm C},  I_{\rm F} = 3.8  {\rm A}, \ {\rm dl/dt} = 100  {\rm A/\mu s^b}$		-	380		ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	4.0		μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	rn-on time	is negligible (turn	-on is do	ninated h	vlaand	•

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.



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#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



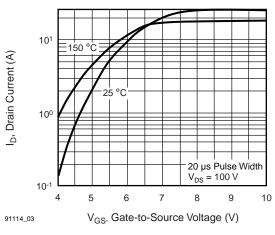


Fig. 3 - Typical Transfer Characteristics

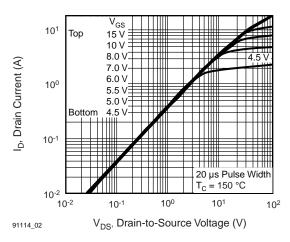


Fig. 2 - Typical Output Characteristics, T<sub>C</sub> = 150 °C

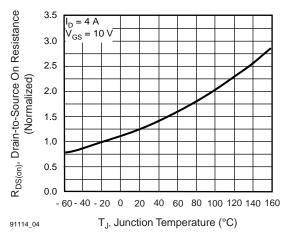


Fig. 4 - Normalized On-Resistance vs. Temperature



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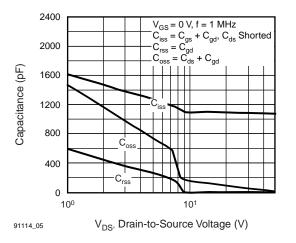


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

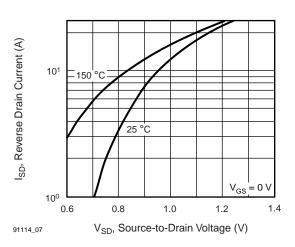


Fig. 7 - Typical Source-Drain Diode Forward Voltage

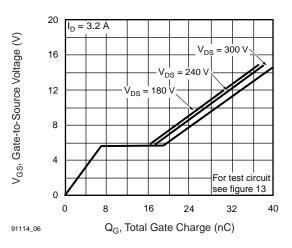


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

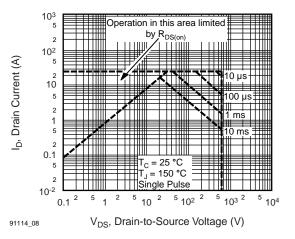


Fig. 8 - Maximum Safe Operating Area



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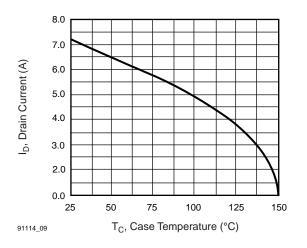


Fig. 9 - Maximum Drain Current vs. Case Temperature

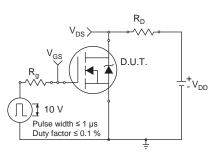


Fig. 10a - Switching Time Test Circuit

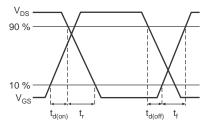


Fig. 10b - Switching Time Waveforms

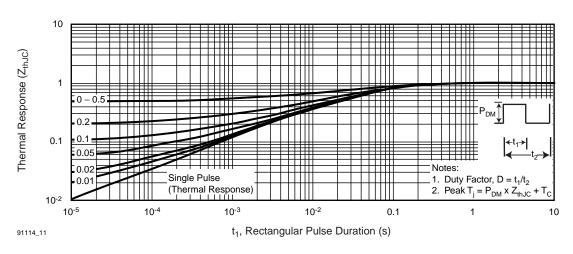


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



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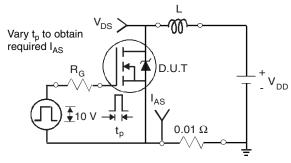


Fig. 12a - Unclamped Inductive Test Circuit

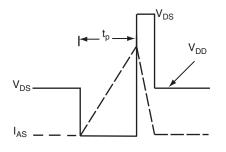


Fig. 12b - Unclamped Inductive Waveforms

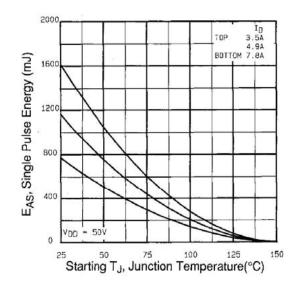


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

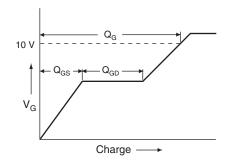


Fig. 13a - Basic Gate Charge Waveform

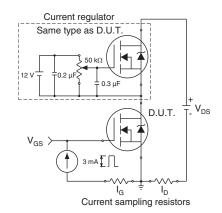
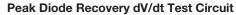
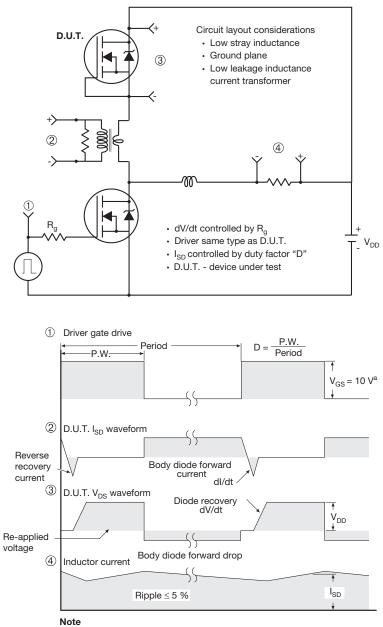


Fig. 13b - Gate Charge Test Circuit



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a.  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel



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